

## **Dual N-Channel 30-V (D-S) MOSFET**

PRODUCT SUMMARY					
V <sub>DS</sub> (V)	$R_{DS(on)}$ ( $\Omega$ )	I <sub>D</sub> (A)	Q <sub>g</sub> (Typ.)		
30	$0.022 \text{ at V}_{GS} = 10 \text{ V}$	6.8	15 nC		
30	0.026 at V <sub>GS</sub> = 4.5 V	6.0	10110		

 $D_1$ 

 $D_2$ 

SO-8

Top View

# **FEATURES**

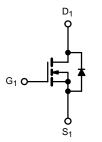
- Halogen-free According to IEC 61249-2-21 Definition
- TrenchFET® Power MOSFET
- 100 % UIS Tested
- 100 % R<sub>g</sub> Tested
- Compliant to RoHS Directive 2002/95/EC

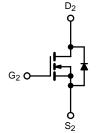


COMPLIANT HALOGEN **FREE** 

#### **APPLICATIONS**

- Set Top Box
- Low Current DC/DC





N-Channel MOSFET

N-Channel MOSFET

<b>ABSOLUTE MAXIMUM RATIN</b>	IGS T <sub>A</sub> = 25 °C,	unless othe	rwise noted	
Parameter	Symbol	Limit	Unit V	
Drain-Source Voltage Gate-Source Voltage		V <sub>DS</sub> V <sub>GS</sub>		30
				± 20
	T <sub>C</sub> = 25 °C		6.8 <sup>a</sup>	
Continuous Drain Current (T <sub>.1</sub> = 150 °C)	T <sub>C</sub> = 70 °C	] [	5.6	
Continuous Brain Current (1) = 100 °C)	T <sub>A</sub> = 25 °C	l <sub>D</sub>	6.2 <sup>b, c</sup>	
	T <sub>A</sub> = 70 °C	1	5.2 <sup>b, c</sup>	Α
Pulsed Drain Current		I <sub>DM</sub>	30	^
Castinuara Carras Brain Binda Currant	T <sub>C</sub> = 25 °C	l <sub>a</sub>	2.25	
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	- I <sub>S</sub>	1.48 <sup>b, c</sup>	
Single Pulse Avalanche Current	1 - 0.1 mH	I <sub>AS</sub>	5	
Single Pulse Avalanche Energy  L = 0.1 mH		E <sub>AS</sub>	1.25	mJ
	T <sub>C</sub> = 25 °C		2.7	
Maximum Dawar Dissination	$T_C = 70 ^{\circ}\text{C}$	P <sub>D</sub>	1.77	W
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	1 <sup>FD</sup>	1.78 <sup>b, c</sup>	VV
	T <sub>A</sub> = 70 °C	1	1.14 <sup>b, c</sup>	
Operating Junction and Storage Temperature Range		$T_J, T_{sta}$	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient <sup>a, c, d</sup>	t ≤ 10 s	R <sub>thJA</sub>	58	70	°C/W	
Maximum Junction-to-Foot (Drain)	Steady State	$R_{th,IF}$	38	45		

#### Notes:

- a. Package limited, T<sub>C</sub> = 25 °C.
  b. Surface Mounted on 1" x 1" FR4 board.
- d. Maximum under Steady State conditions is 110 °C/W.



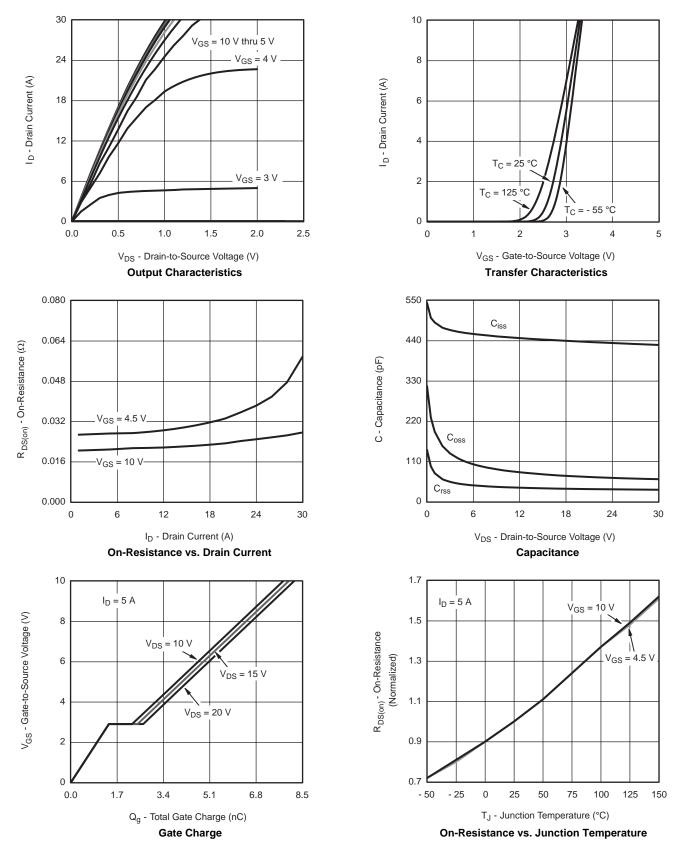
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V <sub>DS</sub>	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	30			V	
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$	J 250 ·· A		32		mV/°C	
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	$I_D = 250  \mu A$		- 5.0			
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}$ , $I_{D} = 250 \mu A$	1.0		2.5	V	
Gate-Source Leakage	I <sub>GSS</sub>	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
		$V_{DS} = 30 \text{ V}, V_{GS} = 0 \text{ V}$			1		
Zero Gate Voltage Drain Current	IDSS	V <sub>DS</sub> = 30 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			10	μΑ	
On-State Drain Current <sup>a</sup>	I <sub>D(on)</sub>	V <sub>DS</sub> ≥ 5 V, V <sub>GS</sub> = 10 V	10			Α	
		$V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		0.022		1	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>	V <sub>GS</sub> = 4.5 V, I <sub>D</sub> = 4 A		0.026		Ω	
Forward Transconductance <sup>a</sup>	g <sub>fs</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 5 A		16		S	
Dynamic <sup>b</sup>							
Input Capacitance	C <sub>iss</sub>			586			
Output Capacitance	C <sub>oss</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		117		pF	
Reverse Transfer Capacitance	C <sub>rss</sub>			55			
·		$V_{DS} = 15 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 5 \text{ A}$		15		nC	
Total Gate Charge	$Q_g$			3.7	5.6		
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS} = 15 \text{ V}, V_{GS} = 4.5 \text{ V}, I_{D} = 5 \text{ A}$		1.4			
Gate-Drain Charge	Q <sub>gd</sub>			1.05			
Gate Resistance	R <sub>g</sub>	f = 1 MHz	0.8	4.3	8.6	Ω	
Turn-On Delay Time	t <sub>d(on)</sub>			12	24		
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 3 $\Omega$		55	100		
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D\cong$ 5 A, $V_{GEN}$ = 4.5 V, $R_g$ = 1 $\Omega$		11	22		
Fall Time	t <sub>f</sub>			8	16		
Turn-On Delay Time	t <sub>d(on)</sub>			4	8	ns	
Rise Time	t <sub>r</sub>	$V_{DD}$ = 15 V, $R_L$ = 3 $\Omega$		9	18	- - -	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong 5 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		10	20		
Fall Time	t <sub>f</sub>			6	12		
<b>Drain-Source Body Diode Characteristi</b>	cs		1				
Continuous Source-Drain Diode Current	I <sub>S</sub>	T <sub>C</sub> = 25 °C			2.25	^	
Pulse Diode Forward Current	I <sub>SM</sub>				24	A	
Body Diode Voltage	V <sub>SD</sub>	$I_{S} = 2 \text{ A}, V_{GS} = 0 \text{ V}$		0.8	1.2	V	
Body Diode Reverse Recovery Time	t <sub>rr</sub>			11	20	ns	
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	L 5 A 41/41 400 A/ T 07 00		4	8	nC	
Reverse Recovery Fall Time	t <sub>a</sub>	$I_F = 5 \text{ A}, \text{ dI/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 ^{\circ}\text{C}$		7			
Reverse Recovery Rise Time	t <sub>b</sub>			4		ns	

#### Notes:

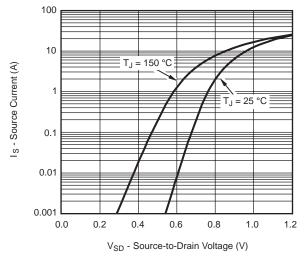
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

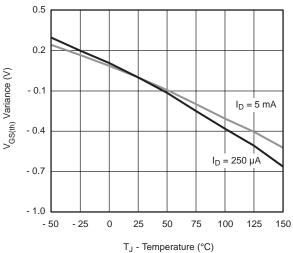




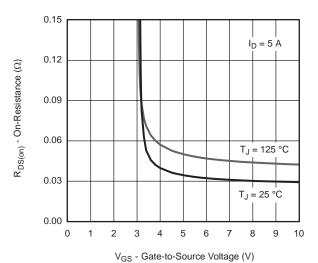




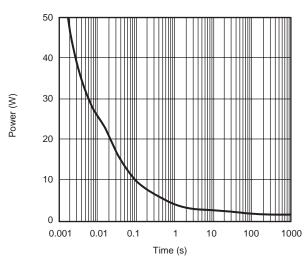
#### Source-Drain Diode Forward Voltage



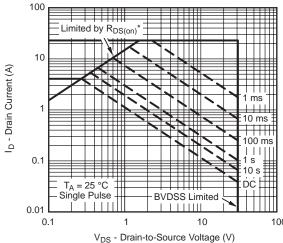
Threshold Voltage



On-Resistance vs. Gate-to-Source Voltage



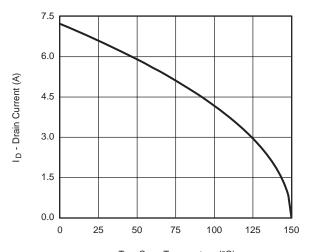
Single Pulse Power



\* V<sub>GS</sub> > minimum V<sub>GS</sub> at which R<sub>DS(on)</sub> is specified

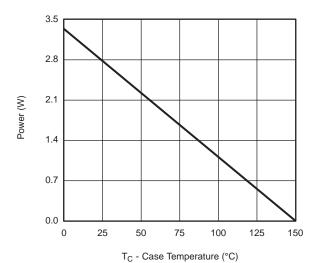
Safe Operating Area, Junction-to-Ambient



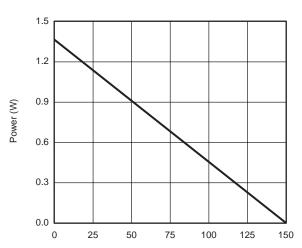


T<sub>C</sub> - Case Temperature (°C)





Power, Junction-to-Foot

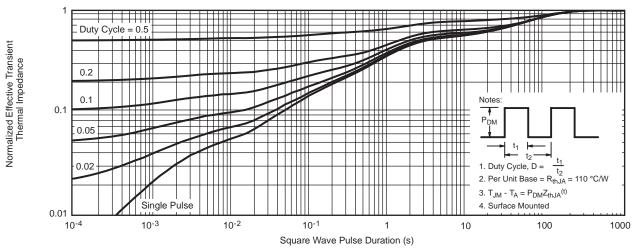


T<sub>A</sub> - Ambient Temperature (°C)

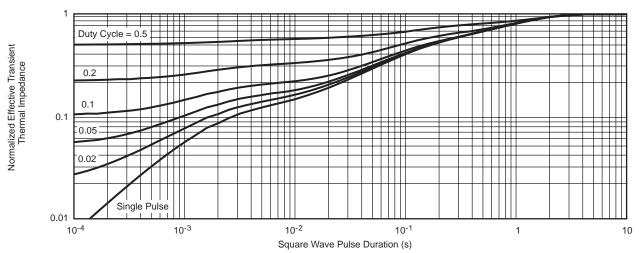
Power, Junction-to-Ambient

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





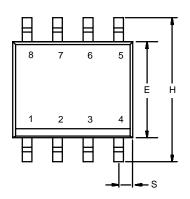
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot



SOIC (NARROW): 8-LEAD JEDEC Part Number: MS-012







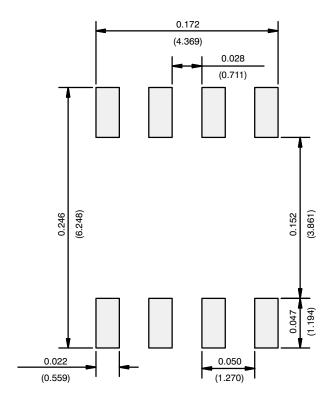
	MILLIMETERS		INC	CHES	
DIM	Min	Max	Min	Max	
Α	1.35	1.75	0.053	0.069	
A <sub>1</sub>	0.10	0.20	0.004	0.008	
В	0.35	0.51	0.014	0.020	
С	0.19	0.25	0.0075	0.010	
D	4.80	5.00	0.189	0.196	
E	3.80	4.00	0.150	0.157	
е	1.27 BSC		0.050 BSC		
Н	5.80	6.20	0.228	0.244	
h	0.25	0.50	0.010	0.020	
L	0.50	0.93	0.020	0.037	
q	0°	8°	0°	8°	
S	0.44	0.64	0.018	0.026	
FCN: C-06527-Rev I 11-Sep-06					

ECN: C-06527-Rev. I, 11-Sep-06

DWG: 5498



#### **RECOMMENDED MINIMUM PADS FOR SO-8**



Recommended Minimum Pads Dimensions in Inches/(mm)



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